## Notice of References Cited Application/Control No. 10/800,181 Examiner YONAS BAYOU Applicant(s)/Patent Under Reexamination LEE ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,963,977	11-2005	Chen et al.	713/183
*	В	US-5,513,133	04-1996	Cressel et al.	708/620
*	С	US-6,658,442	12-2003	Pomet, Alain	708/491
*	D	US-5,847,981	12-1998	Kelley et al.	708/603
*	Е	US-2006/0098824	05-2006	Mao, Wenbo	380/282
*	F	US-2005/0198093	09-2005	Son, Hee-Kwan	708/625
*	G	US-2003/0163503	08-2003	Nguyen, Trinh Huy	708/625
*	Ι	US-5,247,605	09-1993	Engeler, William E.	706/22
*	-	US-2005/0210086	09-2005	Lutz et al.	708/200
*	J	US-2004/0252829	12-2004	Son, Hee-Kwan	380/030
*	K	US-2001/0023425	09-2001	Oberman et al.	708/620
*	L	US-6,668,267	12-2003	Pomet, Alain	708/492
*	М	US-6,317,769	11-2001	Kobayashi et al.	708/491

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.